## Notice of References Cited Application/Control No. 10/772,315 Examiner Maria Veronica D. Ewald Applicant(s)/Patent Under Reexamination YOON ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,468,141	11-1995	lwami et al.	425/542
*	В	US-3,674,401	07-1972	R.E. Annis, Jr. et al.	425/567
*	С	US-6,099,287	08-2000	Higashida et al.	425/190
*	D	US-5,076,339	12-1991	Smith, John J.	164/72
	Ε	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	к	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	T					

## **NON-PATENT DOCUMENTS**

*	·	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	v	
	w	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.